

1998 NEW YORK STATE PROCESSING SWEET CORN RESEARCH ASSOCIATION PROGRESS REPORT
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TITLE: SCREENING OF COMMERCIAL PROCESSING TYPE SWEET CORN FOR RESISTANCE TO EUROPEAN CORN BORER

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ABSTRACT:

The results of this research corroborate last year's results and show that commercial processing sweet corn cultivars have resistance to European corn borer, with some varieties consistently displaying greater resistance when measured by total number of larvae, ear damage, and tunneling damage.

This was a collaborative effort to determine levels of resistance to European corn borer in 19 lines of commercial processing sweet corn cultivars that are commonly grown in New York and the Northeast. Twelve cultivars used in 1997 and seven additional cultivars were monitored for damage caused by artificial infestations of European corn borer. Damage was evaluated to determine if it was feasible to use commercial genotypes for back crossing with other resistance bearing lines. Additionally, the information can be used to provide commercial growers and processors with pest management options.

For a printed copy of the entire report, please contact the NYS IPM office at:

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